PQ Protocol



Company: Moscow State University of

Operator: Default

Instrument Type: Senterra Microscope 785 nm Grating 400
Optics Configuration: Microscope with: 785 nm, Grating 400, CCD

Accessory: None
Instrument Serial Number: Result
Instrument Firmw are Version: Result

OPUS/DB Version: 20090227 / 6.5.9

Overall Test Result FAIL
Test expires: Test failed

Test Date/Time: 2012/01/18 18:30:47

Test Spectra Path: C:\Program Files\OPUS_65\Validation\Data\20120118\183047

Comment:

Max. Deviation Limit:

Wavelength Accuracy Test

1. Peak specified:	391.5 cm -1	1. Peak measured:	391.3 cm -1
Max. Deviation Limit:	3.00 cm -1	Measured Deviation:	0.24 cm -1
2. Peak specified:	857.9 cm -1	2. Peak measured:	857.9 cm -1
Max. Deviation Limit:	3.00 cm -1	Measured Deviation:	0.03 cm -1
3. Peak specified:	1168.5 cm-1	3. Peak measured:	1168.4 cm-1
Max. Deviation Limit:	3.00 cm -1	Measured Deviation:	0.07 cm-1
4. Peak specified:	1323.9 cm-1	4. Peak measured:	1324.2 cm -1
Max. Deviation Limit:	3.00 cm -1	Measured Deviation:	0.33 cm -1
5. Peak specified:	1648.4 cm-1	5. Peak measured:	1648.3 cm-1
Max. Deviation Limit:	3.00 cm -1	Measured Deviation:	0.08 cm -1
6. Peak specified:	2931.1 cm-1	6. Peak measured:	

Throughput Test

Measured Deviation:

Throughput minimum requirement: 2700 Throughput measured: 6943

3.00 cm -1

Photometric Consistency Test

1. Peak specified:	620.9 cm -1	1. Peak measured:	620.5 cm -1
Max. Deviation Limit:	10.000 %	Measured Deviation:	14.760 %
2. Peak specified:	1001.4 cm -1	2. Peak measured:	1001.1 cm-1
Max. Deviation Limit:	10.000 %	Measured Deviation:	0.000 %
3. Peak specified:	1602.3 cm -1	3. Peak measured:	1602.0 cm -1
Max. Deviation Limit:	10.000 %	Measured Deviation:	22.666 %
4. Peak specified:	Not determined.	4. Peak measured:	Not determined.
Max. Deviation Limit:		Measured Deviation:	

5. Peak specified: Not determined. 5. Peak measured: Not determined. Max. Deviation Limit: --- Measured Deviation: ---

Overall Test Result = FAIL



Date and Signature

Date and Signature